

**Notice of References Cited**

Application/Control No.

09/836,860

Applicant(s)/Patent Under  
Reexamination  
HECKMEIER ET AL.

Examiner

Shean C Wu

Art Unit

1756

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4143947	03-1979	Aftergut et al.	252/299.01
	B	US-5156763	10-1992	Gray et al.	252/299.67
	C	US-5334327	08-1994	Gray et al.	252/299.67
	D	US-6348244 B1	02-2001	Miyazawa et al.	428/1.1
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 09-157654	06-1997	Japan	---	---
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	English translation for JP 09-157654 by computer, <a href="http://www6.ipdl.jpo.go.jp/Tokujitu/PAJdetail.ipdl?N0000=60&amp;N0120=01&amp;N2001=2&amp;N3001=H09-157654">http://www6.ipdl.jpo.go.jp/Tokujitu/PAJdetail.ipdl?N0000=60&amp;N0120=01&amp;N2001=2&amp;N3001=H09-157654</a>
	V	
	W	
	X	

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